

Search Notes

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Applicant(s)/Patent under
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SEARCHED

Class	Subclass	Date	Examiner
428	629,632, 668,669	12/4/2006	AB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
427	127-128	12/4/2006	AB
427	130	12/4/2006	AB
427	132	12/4/2006	AB
428/ 629,632, 668,669		12/4/2006	ab

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

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